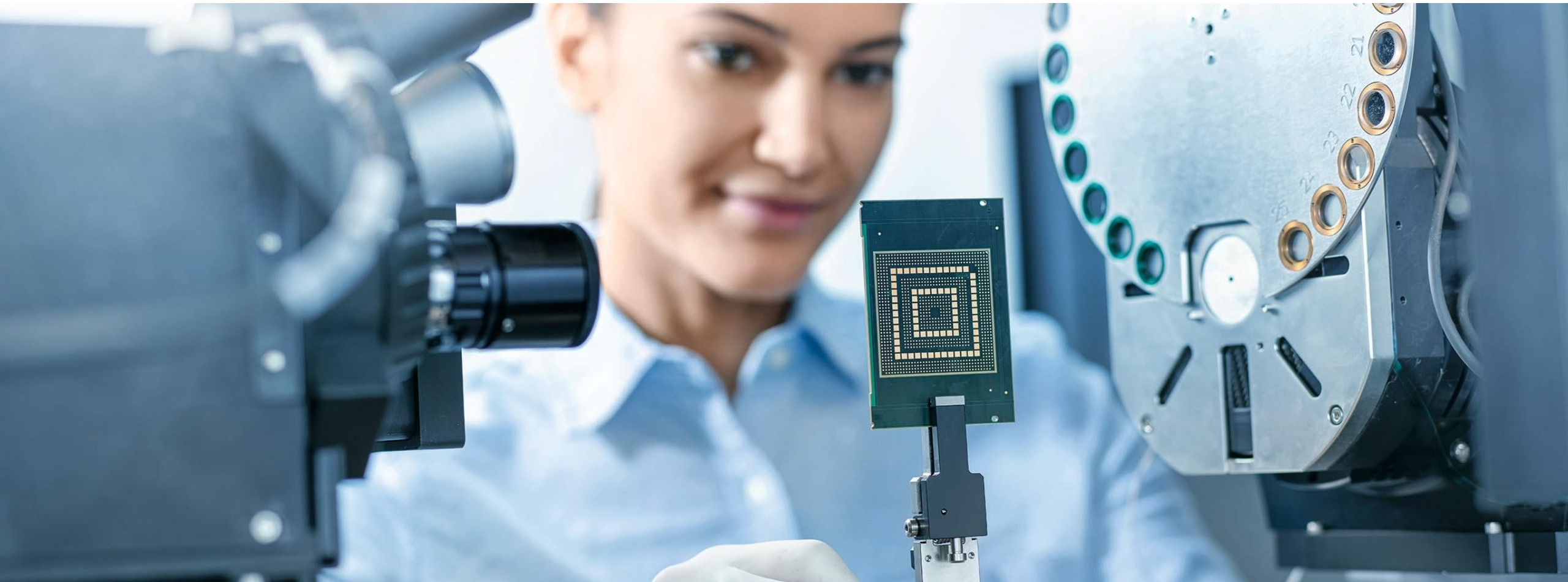


The AI Revolution Through the Lens of Microscopy

Veno Naidoo & Andrew Elliott



11 June 2024



-
- 01** Introduction to ZEISS

 - 02** AI in Microscopy

 - 03** Introduction to X-ray CT

 - 04** AI for CT Reconstruction

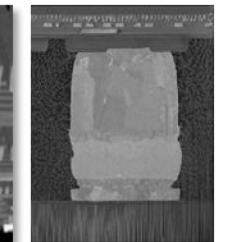
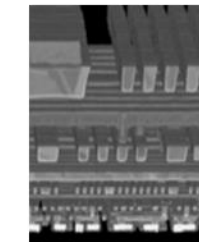
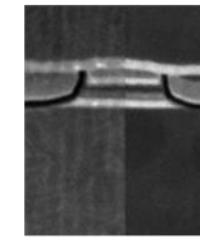
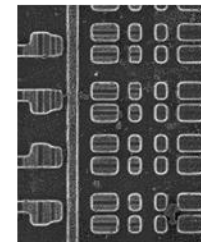
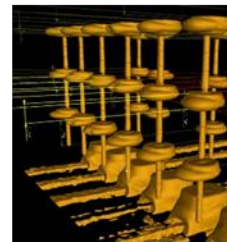
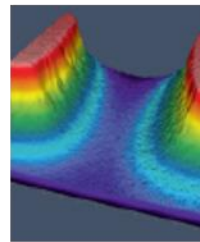
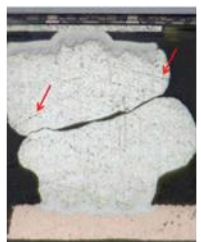
 - 05** AI for Super-resolution

 - 06** Conclusion



Introduction to ZEISS

ZEISS Microscopy Portfolio Across Lengthscales



Digital
Microscope

Upright and
Inverted

Confocal

Submicron
microCT

Submicron
3D X-ray

Nanoscale
3D X-ray

Multi-beam
SEM

FE SEM

Focused
Ion Beam

Laser FIB

250 nm

250 nm

200 nm

950 nm

500 nm

50 nm

<4 nm

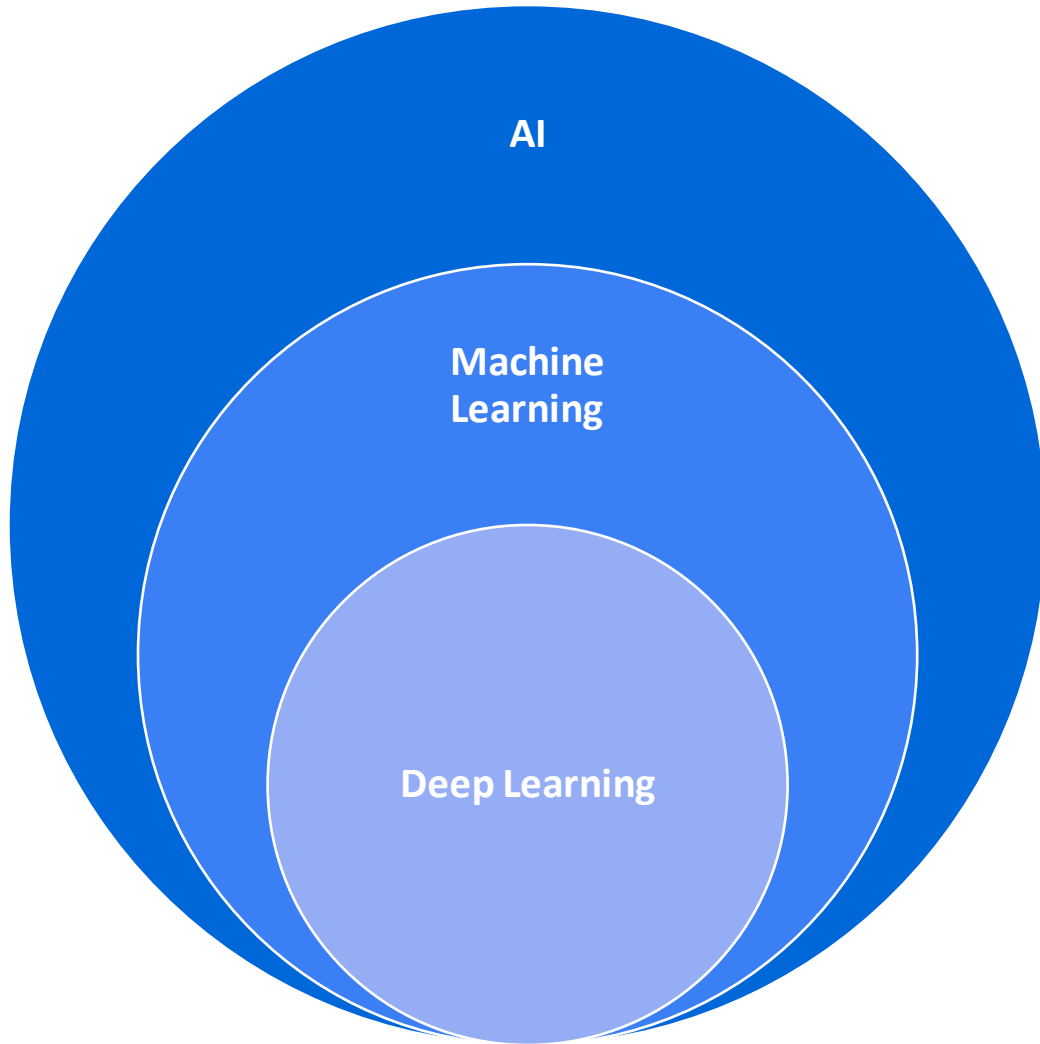
<1 nm

<1 nm

<1 nm



AI in Microscopy



Machine Learning	Requirements	Deep Learning
Yes	Training	Yes
Medium	Size of training dataset	Large
Medium	Processing power	High

Stages in a Microscopy Workflow

Advanced Reconstruction Toolbox

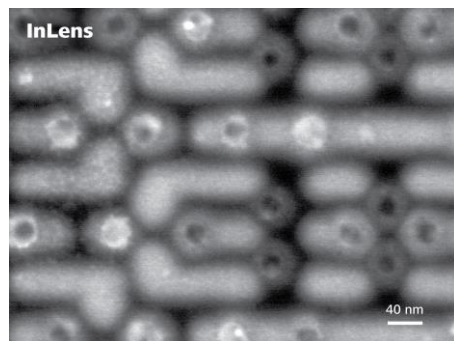


01



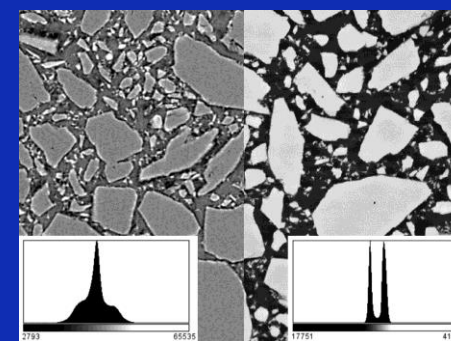
Sample Preparation

02



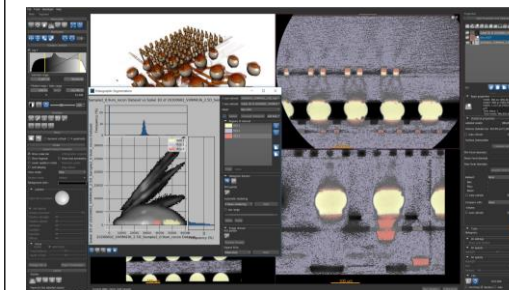
Imaging

03



Processing

04

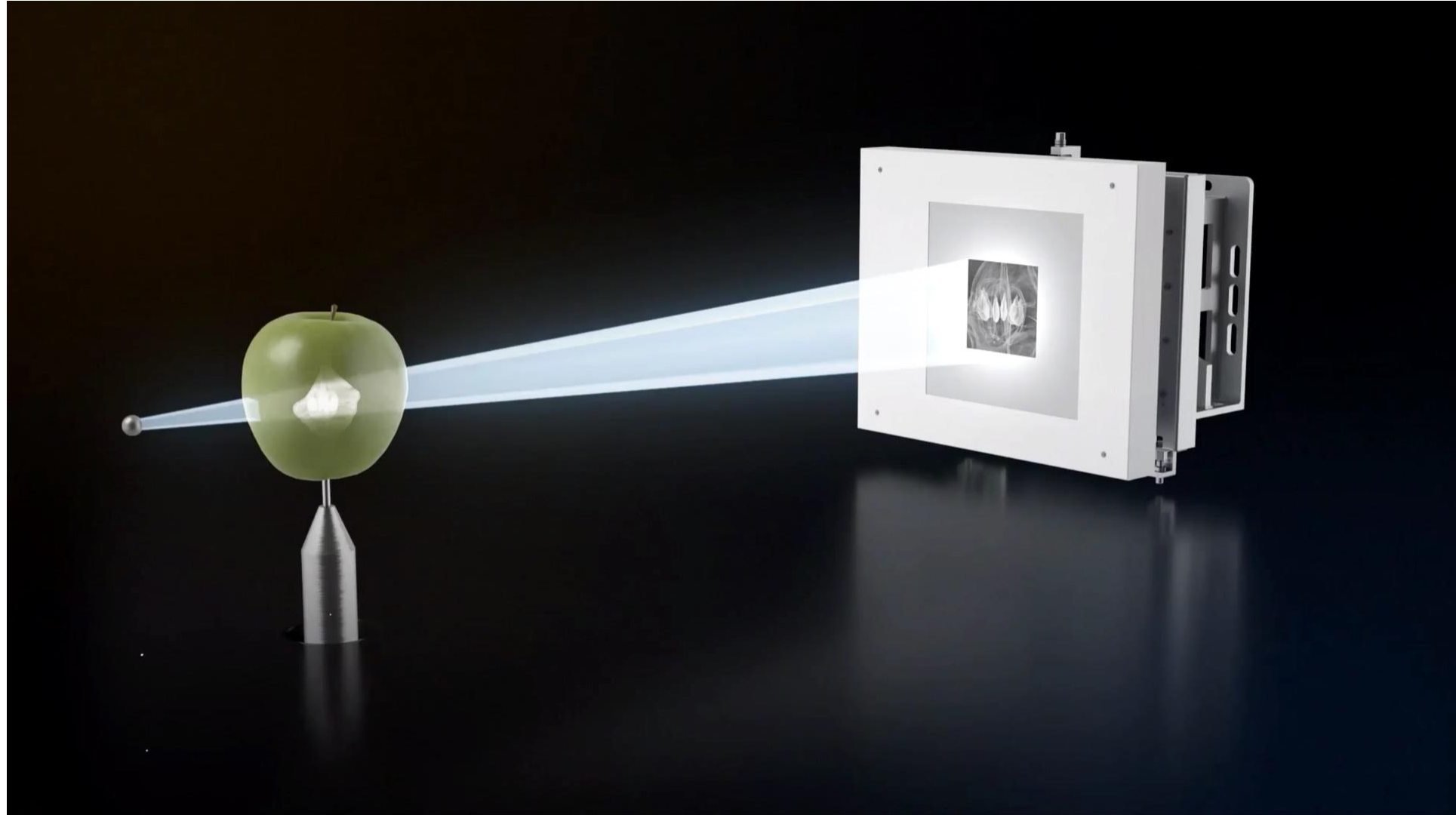


Data Analysis

Introduction to X-ray CT

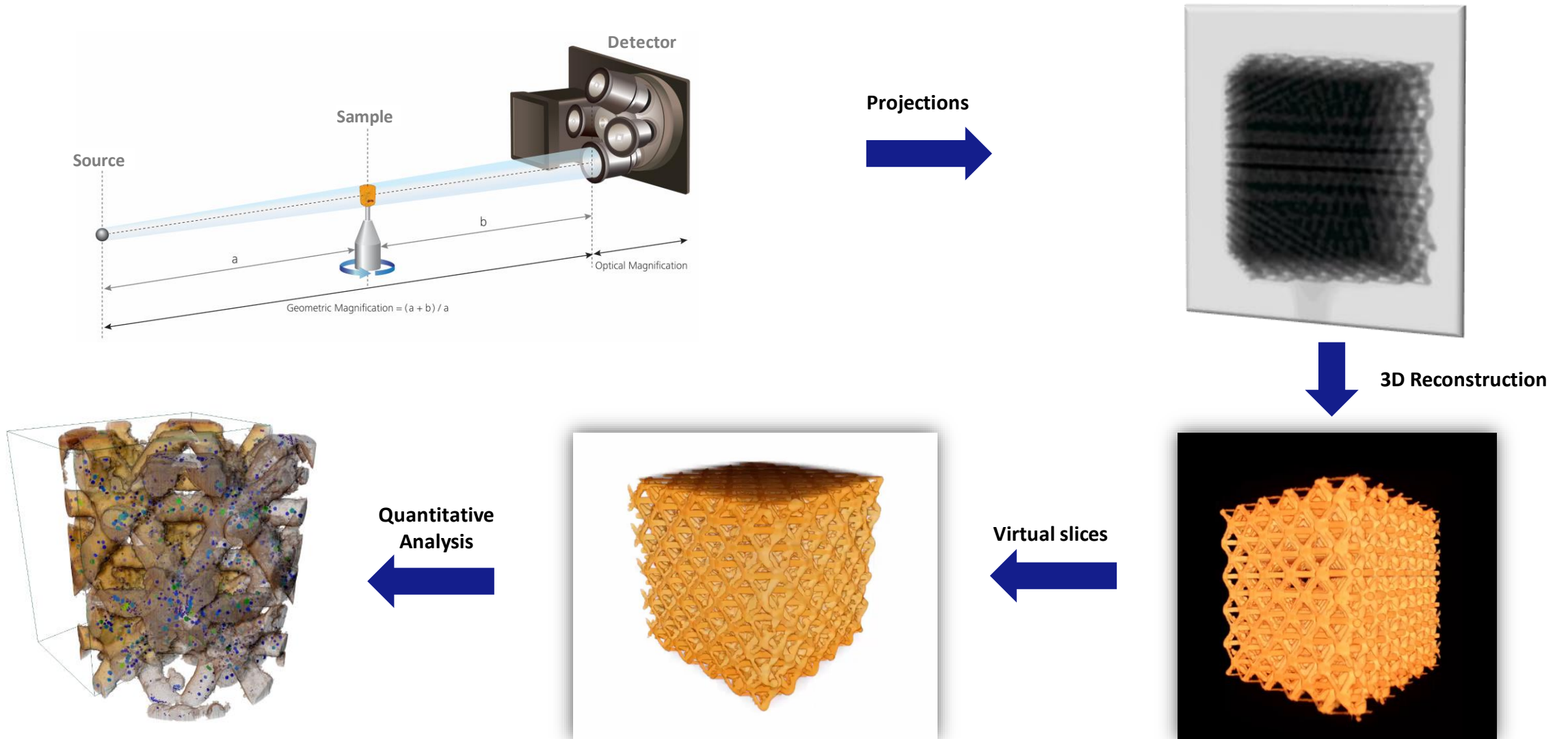
Conventional X-ray microCT

The intrinsic conflict is the resolution and the sample size



X-ray Computed Tomography

How this works



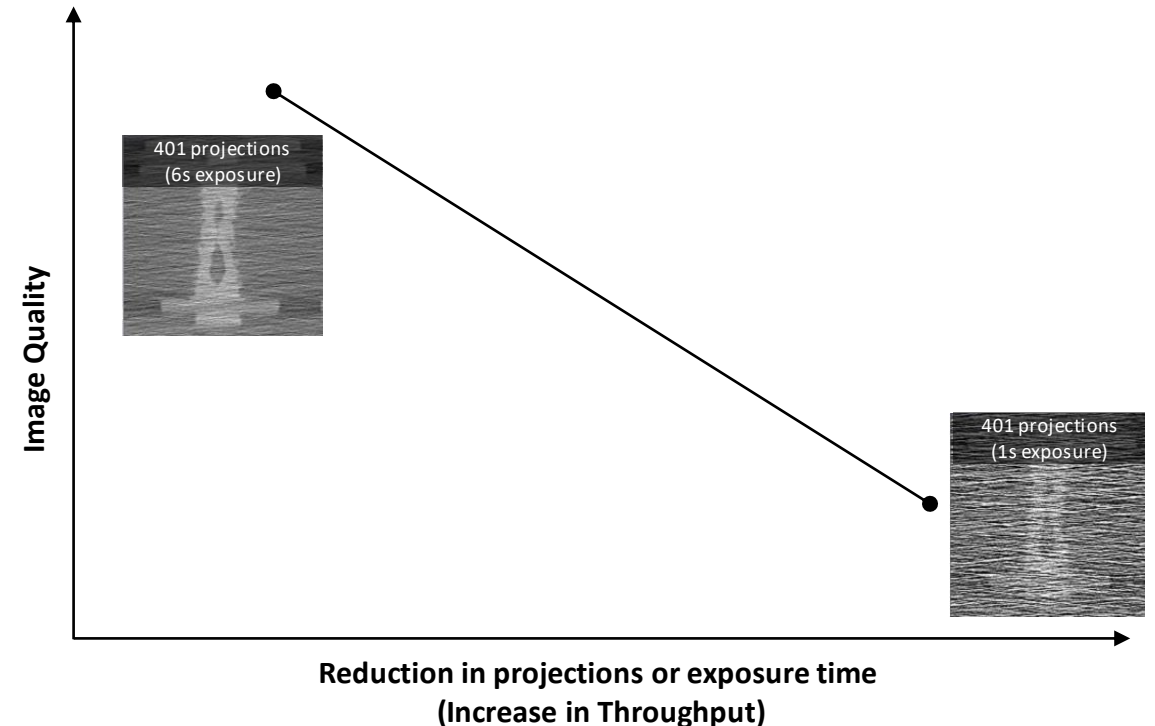
AI for CT Reconstruction

Standard Analytical Reconstruction

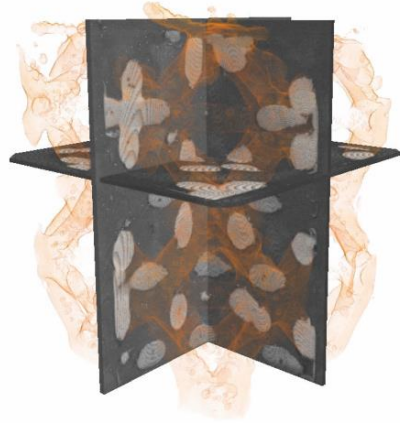
- Currently, XRM uses a standard analytical reconstruction technology known as Filtered Back-Projection also called as **FDK** (Feldkamp) to compute 3D volumes from the 2D projection images.

Key Limitations

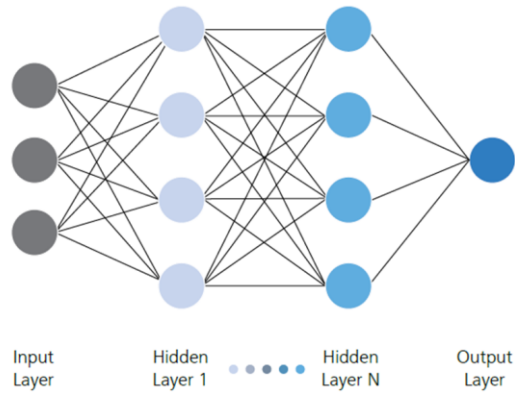
- **Large number of projections** required to avoid limited angle artifacts → **slower scan times**
- **Long exposure times** required to avoid high noise artifacts → **slower scan times**



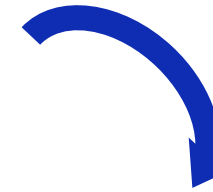
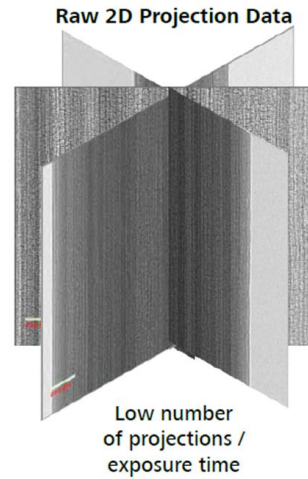
Capture Training Dataset <2 hrs



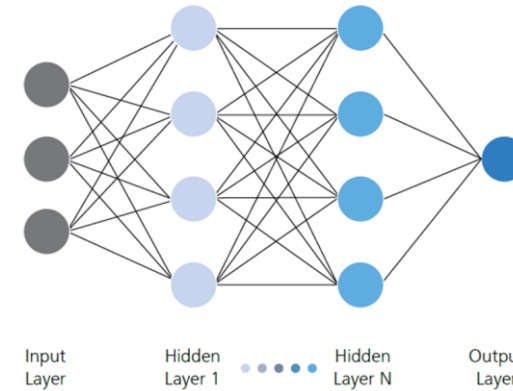
Train CNN Model



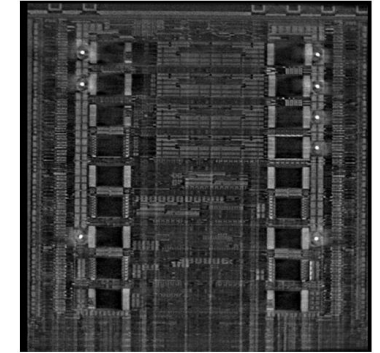
Capture Dataset



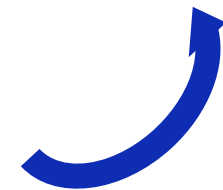
Apply CNN Model



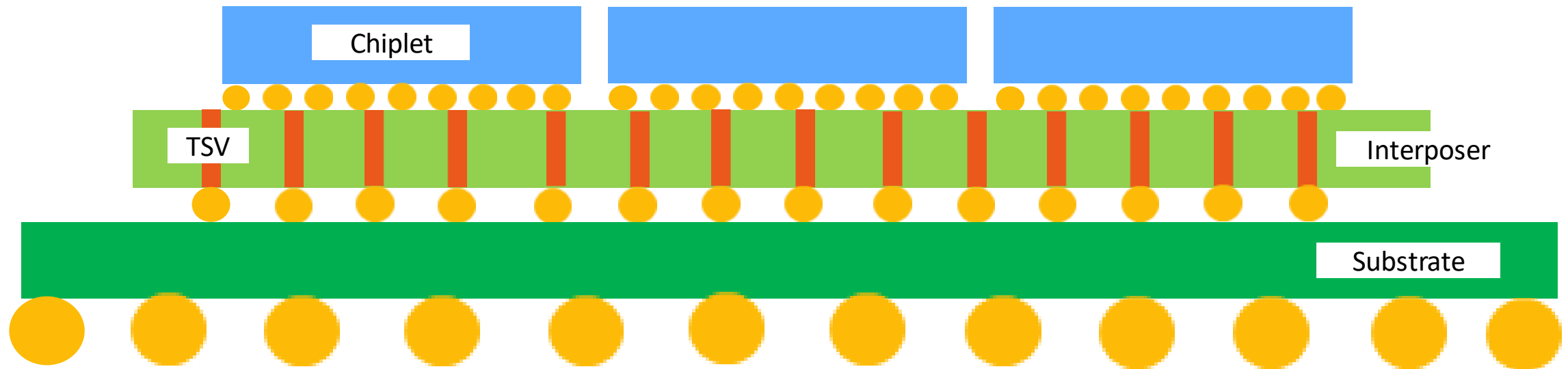
Recon Volume



Low noise
High image quality



Invensas 2.5D Interposer Package



Results: 2.5D Interposer Package



Standard Reconstruction

1,201 projections

Scan time: 120 mins
100 μm

Standard Reconstruction

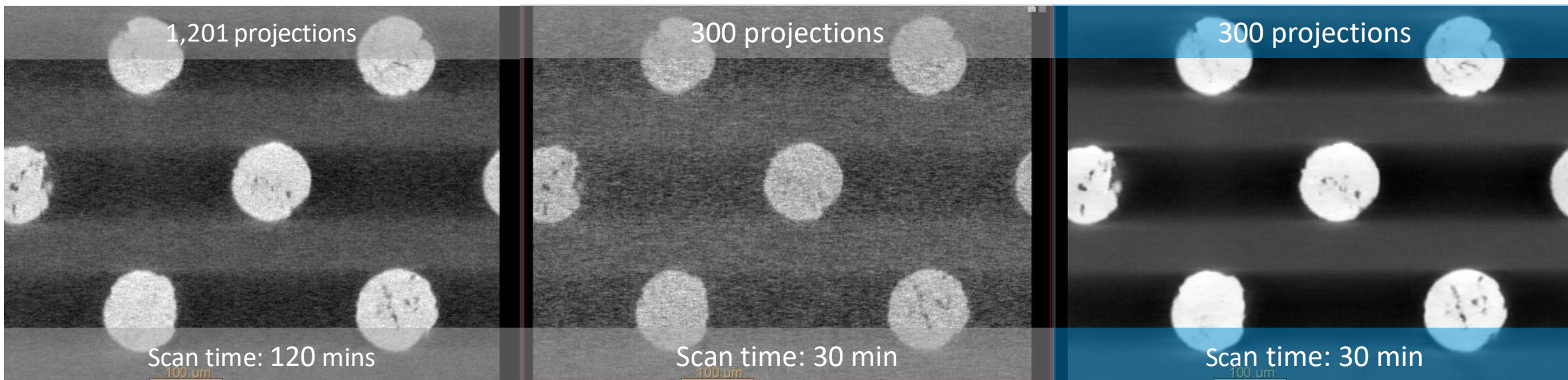
300 projections

Scan time: 30 min
100 μm

DeepRecon Pro

300 projections

Scan time: 30 min
100 μm



Results: 2.5D Interposer Package



Standard Reconstruction

1,201 projections

Scan time: 120 mins
100 μm

Standard Reconstruction

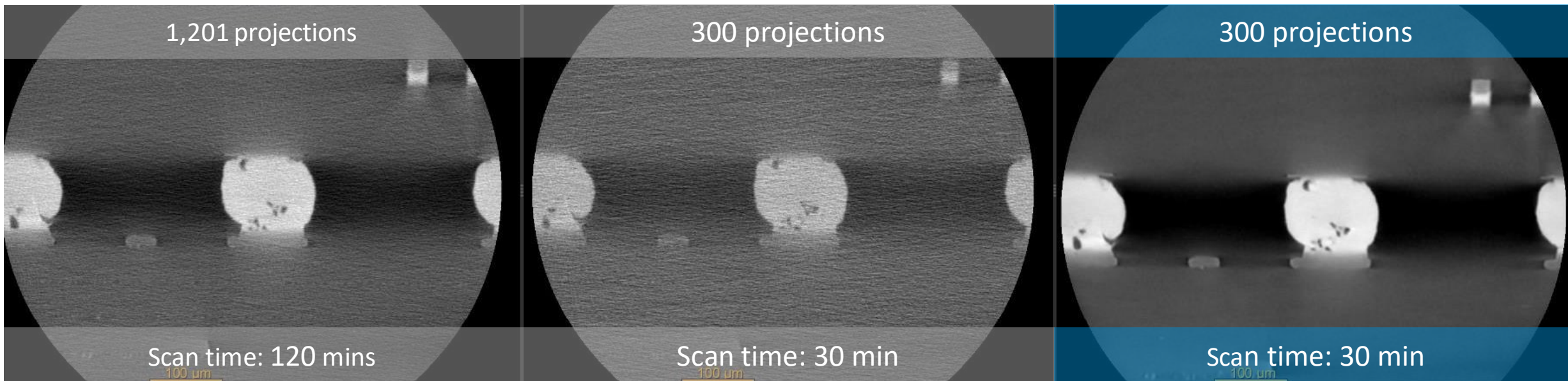
300 projections

Scan time: 30 min
100 μm

DeepRecon Pro

300 projections

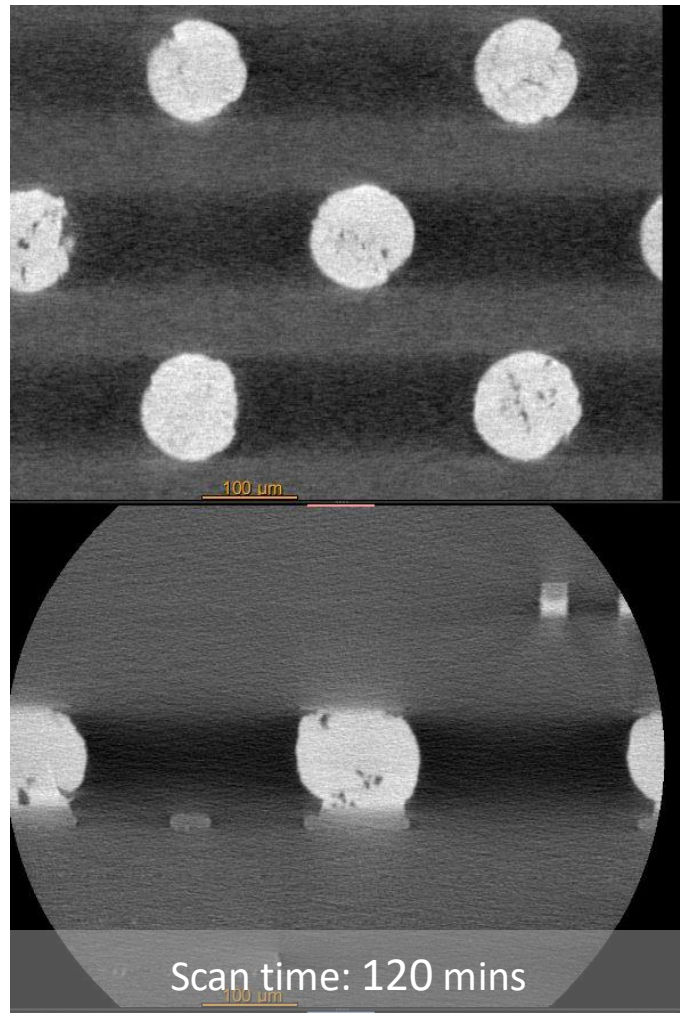
Scan time: 30 min
100 μm



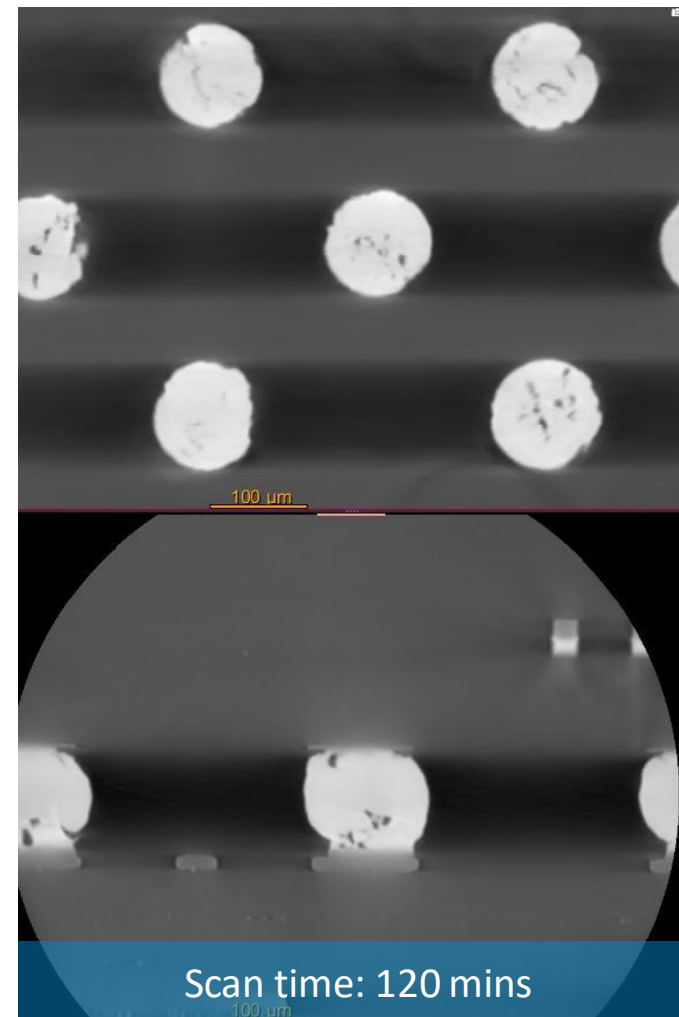
Results: 2.5D Interposer Package



Standard Reconstruction



DeepRecon Pro





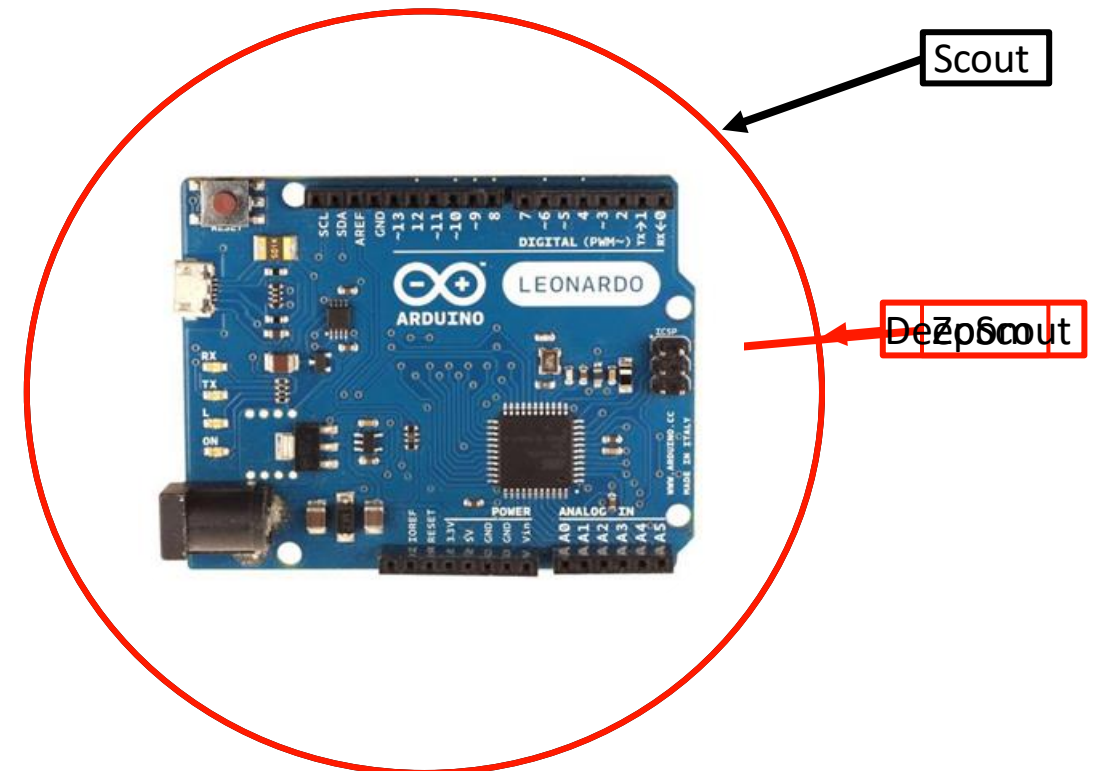
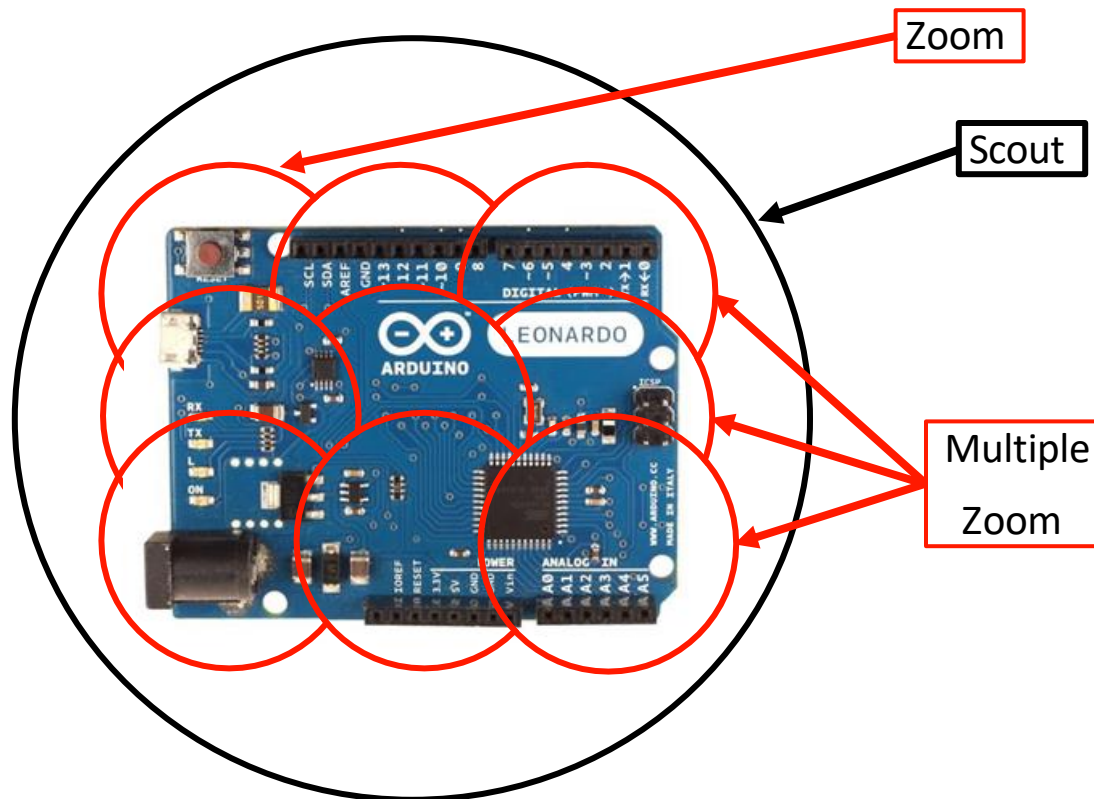
AI for Super-resolution

What is Super-resolution ?

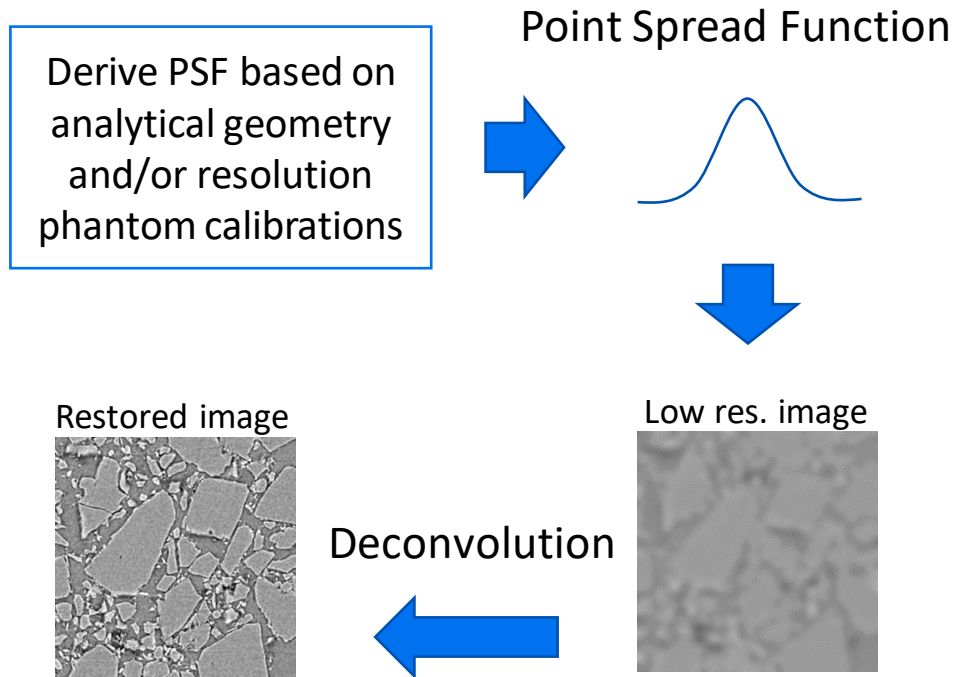
High resolution across large fields of view

Because of the natural trade-off between resolution and field of view (FoV), high resolution across large fields of view is a true challenge for any microscope.

With DeepScout, it is possible to use DeepLearning based methods to recover resolution across large FoV.



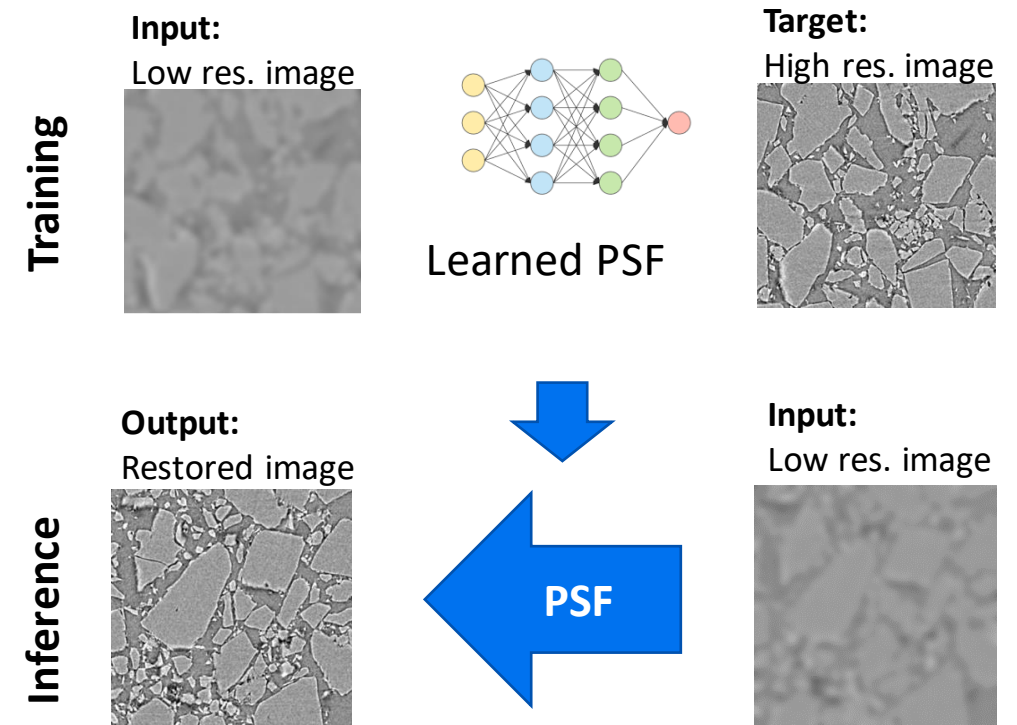
Classical: Analytical/Calibration



Problems with this approach:

- Approximations based on analytical geometry/phantom use may not fit actual sample and acquisition conditions
- Slow
- Increases noise
- Hard to account for anisotropic effects, scatter, etc.

Proposed: Machine Learning assisted



Benefits:

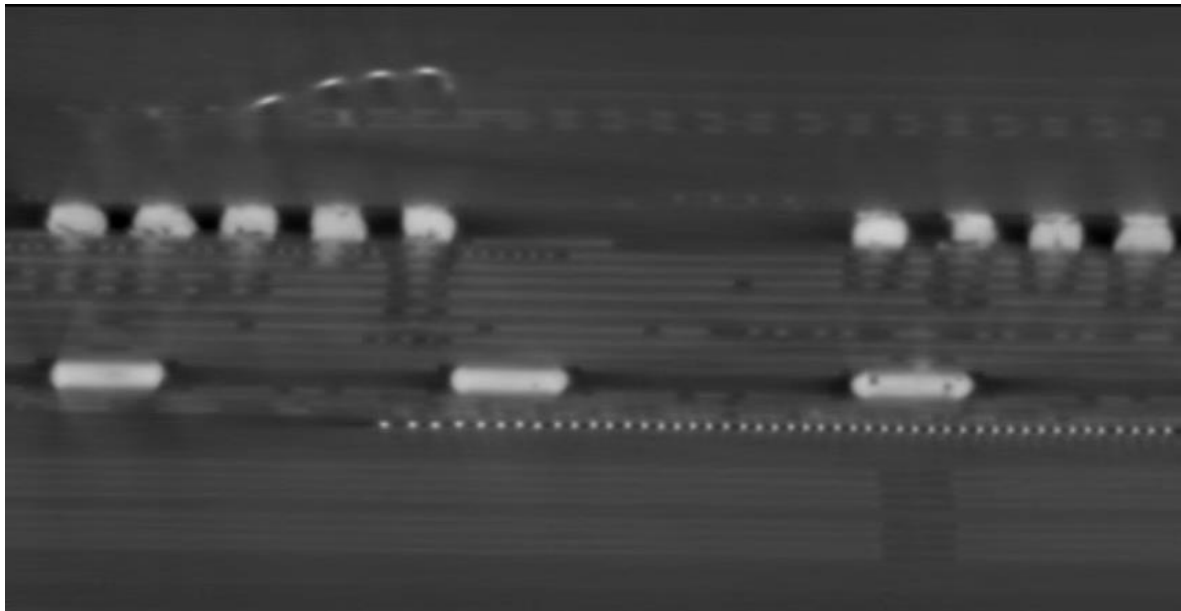
- Tailored to sample class and acquisition conditions
- Easy “calibration”
- Advanced network able to correct for a wide range of resolution effects without noise trade-off

Smartphone A12 Control Board

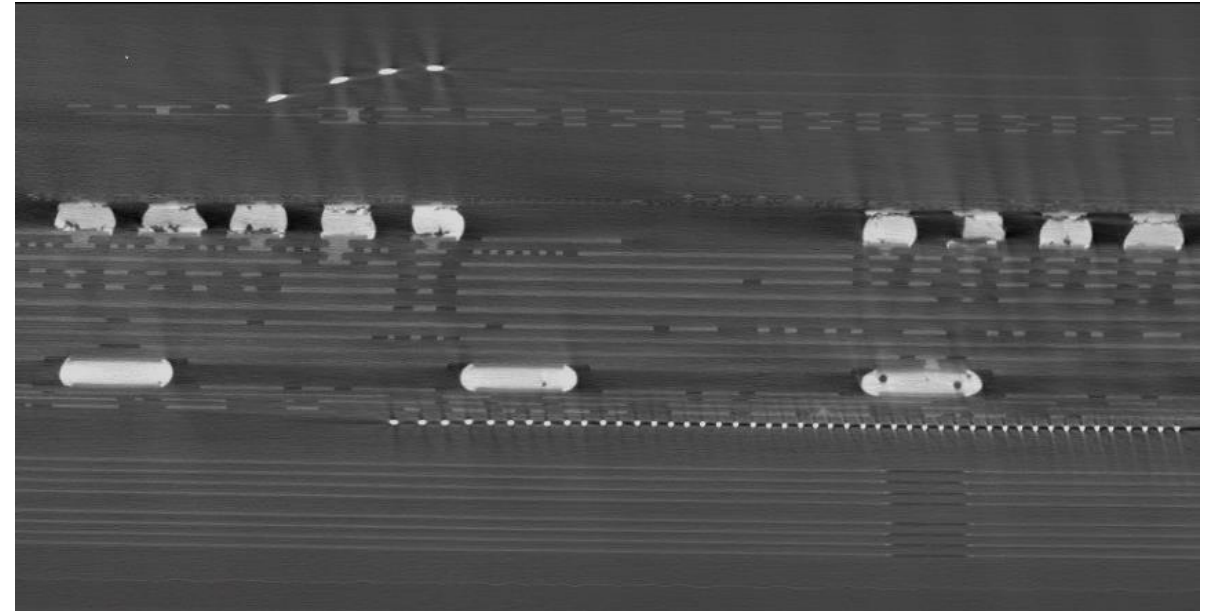
Recovery of Resolution at a Large FOV



Digitally Zoomed-In Large Field of View Image



High Resolution Scan



Smartphone A12 Control Board

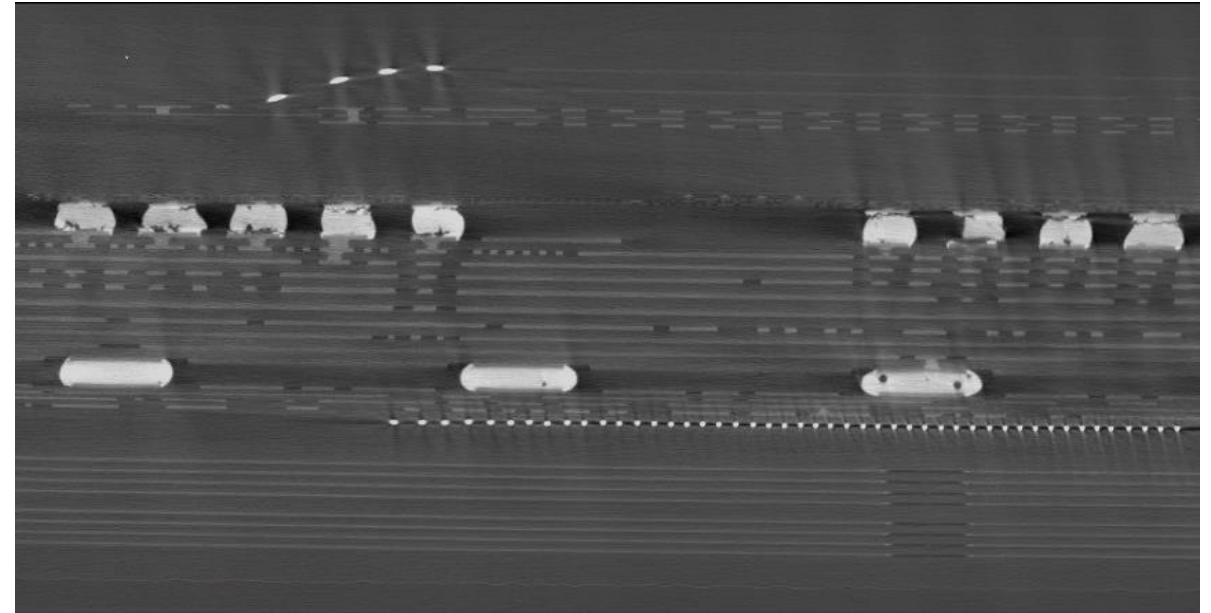
Recovery of Resolution at a Large FOV



AI Resolution Recovered



High Resolution Scan





Conclusion

- AI subsets machine learning and deep learning are seen across many aspect of microscopy, from sample prep to image analysis
- One key area that benefits from deep learning is X-ray CT reconstruction
- Deep Learning can be used to improve both throughput and quality of reconstructed data
- Deep learning can also be used in “super resolution” imaging, significantly reducing time required for collection of high resolution data
- **As long as used sensibly, AI can be a powerful tool in microscopy for improving speed, quality and automation.**



Seeing beyond